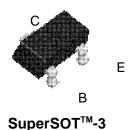


# **FMMT449**



# **NPN Low Saturation Transistor**

These devices are designed with high current gain and low saturation voltage with collector currents up to 2A continuous. Sourced from Process NB.

Absolute Maximum Ratings\* T<sub>A = 25°C unless otherwise noted</sub>

Symbol	Parameter	FMMT449	Units
V <sub>CEO</sub>	Collector-Emitter Voltage	30	V
V <sub>CBO</sub>	Collector-Base Voltage	50	V
V <sub>EBO</sub>	Emitter-Base Voltage	5	V
Ic	Collector Current - Continuous - Peak Pulse Current	1 2	А
T <sub>J,</sub> T <sub>stg</sub>	Operating and Storage Junction Temperature Range	-55 to +150	°C

<sup>\*</sup>These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

#### NOTES:

- 1) These ratings are based on a maximum junction temperature of 150  $^{\circ}\text{C}.$
- 2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Therma	Characteristics	TA = 25°C unless otherwise noted
ınerma	Characteristics	T <sub>A</sub> = 25°C unless otherwise

Symbol	Characteristic	Max	Units
		FMMT449	
P <sub>D</sub>	Total Device Dissipation* Derate above 25°C	500 4	mW mW/°C
R <sub>θJA</sub>	Thermal Resistance, Junction to Ambient	250	°C/W

<sup>\*</sup>Device mounted on FR-4 PCB 4.5" X 5"; mounting pad 0.02 in<sup>2</sup> of 2oz copper.

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(continued)

# **Electrical Characteristics**

 $T_{A\,=\,25^{\circ}C\;unless\;otherwise\;noted}$ 

Symbol	Parameter	Test Conditions	Min	Max	Units
OFF CHAI	RACTERISTICS				
BV <sub>CEO</sub>	Collector-Emitter Breakdown Voltage	I <sub>C</sub> = 10 mA	30		V
BV <sub>CBO</sub>	Collector-Base Breakdown Voltage	I <sub>C</sub> = 1mA	50		V
BV <sub>EBO</sub>	Emitter-Base Breakdown Voltage	I <sub>E</sub> = 100 μA	5		V
I <sub>CBO</sub>	Collector Cutoff Current	V <sub>CB</sub> = 40 V V <sub>CB</sub> = 40 V, Ta=100°C		100 10	nA uA
I <sub>EBO</sub>	Emitter Cutoff Current	V <sub>EB</sub> = 4V		100	nA
ON CHAR	ACTERISTICS*				
h <sub>FE</sub>	DC Current Gain	$I_C = 50 \text{ mA}, V_{CE} = 2V$	70		-
		$I_C = 500 \text{ mA}, V_{CE} = 2V$	100	300	
		$I_C = 1A$ , $V_{CE} = 2V$	80		
		$I_C = 2A$ , $V_{CE} = 2V$	40		
V <sub>CE(sat)</sub>	Collector-Emitter Saturation Voltage	$I_C = 1 \text{ A}, I_B = 100 \text{ mA}$		500	mV
(,		I <sub>C</sub> = 2 A, I <sub>B</sub> = 200 mA		1.0	V
V <sub>BE(sat)</sub>	Base-Emitter Saturation Voltage	I <sub>C</sub> = 1 A, I <sub>B</sub> = 100 mA		1.25	V
V <sub>BE(on)</sub>	Base-Emitter On Voltage	I <sub>C</sub> = 1 A, V <sub>CE</sub> = 2 V		1	V
SMALL SI	GNAL CHARACTERISTICS				
C <sub>obo</sub>	Output Capacitance	V <sub>CB</sub> = 10 V, I <sub>E</sub> = 0, f = 1MHz		15	pF
f <sub>T</sub>	Transition Frequency	I <sub>C</sub> = 50mA,V <sub>CE</sub> = 10 V, f=100MHz	150		MHz

\*Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2.0%

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E<sup>2</sup>CMOS<sup>™</sup> PowerTrench<sup>™</sup>

FACT<sup>TM</sup> QS<sup>TM</sup>

 $\begin{array}{lll} \text{FACT Quiet Series}^{\text{TM}} & \text{Quiet Series}^{\text{TM}} \\ \text{FAST}^{\text{\tiny{\$}}} & \text{SuperSOT}^{\text{TM}}\text{-3} \\ \text{FASTr}^{\text{TM}} & \text{SuperSOT}^{\text{TM}}\text{-6} \\ \text{GTO}^{\text{TM}} & \text{SuperSOT}^{\text{TM}}\text{-8} \\ \text{HiSeC}^{\text{TM}} & \text{TinyLogic}^{\text{TM}} \\ \end{array}$ 

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